



IMAGING WITH RADIATION: 4th South African Biennial Conference
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Nikon Metrology's new 225 kV microfocus X-ray CT

Content

A unique combination of five innovative features has been incorporated into Nikon Metrology's new 225 kV microfocus X-ray CT (computed tomography) system, the XT H 225 ST 2x. As its suffix implies, it offers twice the data acquisition speed and doubles the filament lifetime, considerably extending the system uptime. Doubling inspection productivity raises the system's suitability for quality control (QC) applications on the shop floor, whether in vehicle component manufacture or any serial production environment. It heralds a major increase in factory efficiency by meeting the changing requirements of today's manufacturing sector, whereby QC is starting to drive the operation and optimisation of production lines, an ethos known as Quality 4.0.

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